

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10661503	HIKAWA ET AL.
	Examiner	Art Unit
	PHILIP C LEE	2452

SEARCHED

Class	Subclass	Date	Examiner
709	106,224	7/18/08	/pl/
707	10	7/18/08	/pl/
717	102	7/18/08	/pl/

SEARCH NOTES

Search Notes	Date	Examiner
keywords search in EAST	7/18/08	/pl/
keywords search in 709/106,224; 707/10; 717/102 in EAST	7/18/08	/pl/
keywords search in EAST	2/25/09	/pl/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner